

CERTIFICATE OF ANALYSIS

83X PR3 (batch F)

Certified Reference Material Information

Type: LEAD WITH IMPURITIES (CAST)
Form and Size: Disc 40mm Diameter x 15mm Thickness
Produced by: Universal Scientific Laboratory Pty Ltd
Certified and supplied by: MBH Analytical Ltd

Assigned Values

Percentage element by weight

Element	Sn	Sb	Bi	Cu	Cd	As	Ni	Ag
Value ¹	0.050	0.095	0.162	0.0551	0.0479	0.0017	0.0142	0.0033
Uncertainty ²	0.002	0.003	0.007	0.0017	0.0018	0.0003	0.0009	0.0002

Element	In	Tl	Te	Se	Au	Na	Zn	Hg
Value ¹	0.0069	0.0125	0.0021	0.0104	0.0041	0.0026	(0.0011)	0.0103
Uncertainty ²	0.0007	0.0008	0.0003	0.0007	0.0005	0.0003	-	0.0009

Note: values given in parentheses are not certified - they are provided for information only.

Definitions

- ¹ The certified values are the present best estimates of the true content for each element. Each value is a panel consensus, based on the averaged results of an interlaboratory testing programme, detailed on page 3.
- ² The uncertainty values are generated from the 95% confidence interval derived from the wet analysis results, in combination with a statistical assessment of the homogeneity data, as described on page 2.

Certified by:

MBH ANALYTICAL LIMITED _____

on 4th September 2008

C Eveleigh



Method of Preparation

This reference material was produced from commercial purity lead; the alloy and trace elements were added as single elements or as binary alloys. The melt was cast by sequential transfer of aliquots into individual iron moulds. Approximately 2mm has been removed from the working face of each disc, to minimise any surface effects.

Sampling

Samples for chemical analysis were taken from various positions throughout the casting process. At least 10% of all discs were selected for non-destructive homogeneity testing.

Homogeneity

The discs were checked for sample and batch uniformity using an optical emission spectrometer.

Using the combined data for each surface, standard deviation values were derived for each element as an indicator of any non-homogeneity (as determined for the specific sample size taken by the spectrometer).

Chemical Analysis

Analysis was carried out on millings taken from samples representative of the product. It was performed by a panel of laboratories mostly operating within the terms of EN ISO/IEC 17025 - 2000, using documented standard reference methods and validated by appropriate reference materials.

The individual values listed overpage are the average of each analyst's results.

Estimation of Uncertainties

Each element certified has been analysed by several laboratories, and 95% half-width confidence intervals ($C_{(95\%)}$) for the resultant mean values have been derived by the method shown on page 3.

As a separate exercise, the degree of non-homogeneity of the batch for each element has been quantified by a programme of non-destructive application testing, discussed above.

The final certified uncertainty for each element has been derived by combining these two factors, using the square-root of the summed squares.

Traceability

Most of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to a national authority. It is part of the requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised primary reference materials.

Usage

Intended use: With optical emission and X-ray fluorescence spectrometers.

Recommended method of use: Lead and its alloys are generally prepared by machining on a lathe. However, users are recommended to follow the calibration and sample preparation procedures specified by the relevant instrument manufacturer.

Preparation should be the same for reference materials and the samples for test.

A minimum of five consistent replicate analyses is recommended to provide the necessary sample size. Users are advised to check against possible bias between reference materials and production samples due to differences in metallurgical history, and be aware of possible inter-element effects.

Analytical Data

Percentage element by weight

Sample	Sn	Sb	Bi	Cu	Cd	As	Ni	Ag
1	0.0451	0.0867	0.144	0.0507	0.0438	0.0011	0.0123	0.0027
2	0.0455	0.0908	0.147	0.053	0.0439	0.0012	0.0125	0.0029
3	0.0468	0.0920	0.149	0.0531	0.0453	0.0012	0.0128	0.0030
4	0.0472	0.0926	0.156	0.0532	0.0458	0.0013	0.0129	0.0030
5	0.0477	0.0932	0.161	0.0532	0.0460	0.0015	0.0133	0.0030
6	0.0488	0.0943	0.161	0.0544	0.0472	0.0015	0.0138	0.0032
7	0.0500	0.0947	0.162	0.0546	0.0475	0.0016	0.0142	0.0033
8	0.0516	0.0970	0.162	0.0546	0.0482	0.0019	0.0144	0.0034
9	0.0519	0.0973	0.166	0.0551	0.0488	0.0020	0.0146	0.0035
10	0.053	0.1001	0.170	0.0553	0.0500	0.0022	0.0152	0.0035
11	0.0532	0.1022	0.173	0.0585	0.0505	0.0025	0.0154	0.0036
12	0.0556		0.176	0.0602	0.0518	0.0027	0.0167	0.0039
13	0.057		0.180	0.0602	0.0536		0.017	
Mean	0.0503	0.0946	0.162	0.0551	0.0479	0.0017	0.0142	0.0033
Std Dev	0.0038	0.0044	0.011	0.0029	0.0030	0.0005	0.0015	0.0003
C_(95%)	0.0023	0.0029	0.007	0.0017	0.0018	0.0003	0.0009	0.0002

Sample	In	Tl	Te	Se	Au	Na	Zn	Hg
1	0.0056	0.0103	0.0015	0.0085	0.0030	0.0019	0.0004	0.0086
2	0.0057	0.0117	0.0016	0.0092	0.0035	0.0021	0.0005	0.0090
3	0.0060	0.0120	0.0016	0.0097	0.0035	0.0025	0.0010	0.0090
4	0.0067	0.0125	0.0020	0.0098	0.0038	0.0025	0.0010	0.0097
5	0.0068	0.0125	0.0020	0.0098	0.0042	0.0025	0.0010	0.0098
6	0.0070	0.0126	0.0020	0.0101	0.0044	0.0027	0.0011	0.0109
7	0.0071	0.0127	0.0022	0.0104	0.0045	0.0028	0.0012	0.0110
8	0.0072	0.0127	0.0024	0.0105	0.0046	0.0030	0.0012	0.0112
9	0.0080	0.0136	0.0024	0.0108	0.0047	0.0031	0.0012	0.0115
10	0.0085	0.0148	0.0030	0.0112	0.0050		0.0014	0.0122
11				0.0121			0.0014	
12				0.0122			0.0016	
Mean	0.0069	0.0125	0.0021	0.0104	0.0041	0.0026	0.0011	0.0103
Std Dev	0.0009	0.0012	0.0005	0.0011	0.0007	0.0004	0.0003	0.0012
C_(95%)	0.0007	0.0008	0.0003	0.0007	0.0005	0.0003	0.0002	0.0009

Note: C_(95%) is the 95% half-width confidence interval derived from the equation:

$$C_{(95\%)} = (t \times SD) / \sqrt{n}$$

where n is the number of available values, t is the Student's t value for n-1 degrees of freedom, and SD is the standard deviation of the test results.

Participating Laboratories

Sheffield Assay Office	Sheffield, England	UKAS accreditation 0012
Laboratory Testing, Inc	Hatfield, PA, USA	A2LA accreditation 0117
Genitest, Inc	Montreal, Canada	PRI accreditation 123077
Universal Scientific Laboratory Pty Ltd	Milperra, NSW, Australia	NATA accreditation 492
Luo Yang Copper	Luo Yang, He Nan, China	CNAL accreditation 0173
Institute of Iron & Steel Technology	Shanghai, China	CNAL accreditation 0783
TCR Engineering Services Ltd	Mumbai, India	NABL accreditation 0367
Sargam Metals Pvt Ltd	Chennai, India	NABL accreditation 0025
Shriram Institute for Industrial Research	Delhi, India	NABL accreditation 0045
Laboratory TUV-Nord	Brno, Czech Republic	CAI accreditation 1060
Rotech Laboratories Ltd	Wednesbury, England	
De Bruyn Spectroscopic Solutions Ltd	Johannesburg, South Africa	
London & Scandinavian Met Co	Rotherham, England	
Laboratory Inppamet	Calama, Chile	

Note: to achieve the above-noted accreditation (eg UKAS, NATA, A2LA, etc), test houses must demonstrate conformity to the general requirements of EN ISO/IEC 17025.

Analytical Methods Used

ELEMENT	RESULT No. & METHOD			
	ICP-AES	FAAS		OTHER
Tin	3, 6, 7, 9, 12, 13	1, 2, 4, 5, 11	8, 10	photometric (phenyl fluorone)
Antimony	1, 2, 4, 5, 9, 11	3, 6-8, 10		
Bismuth	2-6, 8	1, 7, 9, 12, 13	10, 11	photometric (iodide)
Copper	1-4, 9, 10, 12	5-8, 11, 13		
Cadmium	1-5, 8, 11, 13	6, 7, 9, 10, 12		
Arsenic	2-6, 9, 10, 12	1, 7, 8	11	ICP-MS
Nickel	3, 4, 6, 8-10, 12, 13	1, 2, 5, 7, 11		
Silver	1, 3, 8-11	2, 4-7, 12		
Indium	1-3, 5-7, 9, 10	4, 8		
Thallium	1-4, 6-8, 10	9	5	ICP-MS
Tellurium	1-3, 5, 6, 9, 10	4, 8	7	ICP-MS
Selenium	1, 3-7, 9-11	2, 12	8	ICP-MS
Gold	1-3, 6, 9	4, 7, 8, 10	5	ICP-MS
Sodium	1, 3, 6, 7, 9	2, 4, 5, 8		
Zinc	2, 4, 5, 8-10, 12	1, 3, 6, 7, 11		
Mercury	1-7, 9	10	8	CV-AAS

Notes

This Certified Reference Material has been produced and certified in accordance with the requirements of ISO Guide 34-2000, ISO Guide 31-2000 and ISO Guide 35-1989, taking into account the requirements of the ISO Guide to the Expression of Uncertainty in Measurement (GUM).

The unidirectional solidification effects associated with semi-chill casting have led to the formation of inhomogeneous segregates in the rear portion of the disc. The above certification is therefore only applicable from the front face of the disc to a depth of 12mm. The rear portion of the disc, to a depth of ~3mm, is not certified.

This material is liable to superficial corrosion, and there is some possibility of microstructural changes due to recrystallisation; however, it will otherwise remain stable provided adequate precautions are taken to protect it from cross-contamination, extremes of temperature and atmospheric moisture. All production records will be retained for a period of 20 years from the date of this certificate. This certification will therefore expire in September 2028, although we reserve the right to make changes as issue revisions, in the intervening period.

This sample is also available in the form of chippings.

The manufacture, analysis and certification of this product were supervised by C Eveleigh, PhD, Technical Director, MBH Analytical Ltd.

The material to which this certificate of analysis refers is supplied subject to our general conditions of sale.